

Tomonaga-Luttinger Liquid Features in Ballistic Single-Walled Carbon Nanotubes: Conductance and Shot Noise

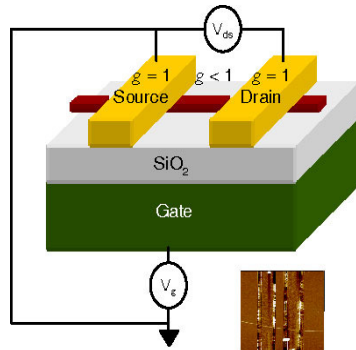
Kim, Recher, Oliver, Yamamoto – Ginzton laboratory, Stanford
Kong, H. Dai – Chemistry department, Stanford

Abstract:

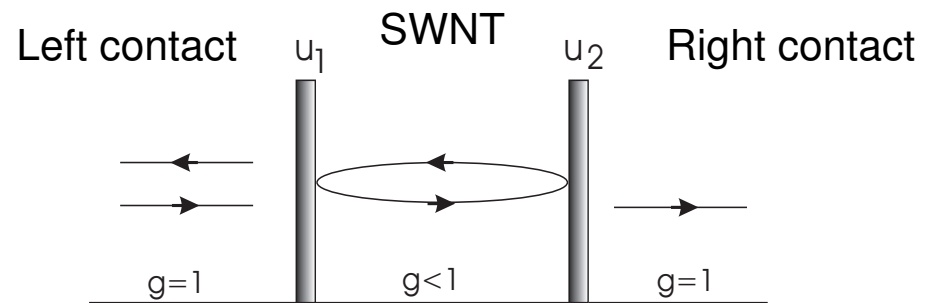
We study the electrical transport properties of well-contacted ballistic single-walled carbon nanotubes in a three-terminal configuration at low temperatures. We observe signatures of strong electron-electron interactions: the conductance exhibits bias-voltage-dependent amplitudes of quantum interference oscillation, and both the current noise and Fano factor manifest bias-voltage-dependent power-law scalings. We analyze our data within the Tomonaga-Luttinger liquid model using the non-equilibrium Keldysh formalism and find qualitative and quantitative agreement between experiment and theory.

Non linear conductance: Fabry-Perot Oscillation

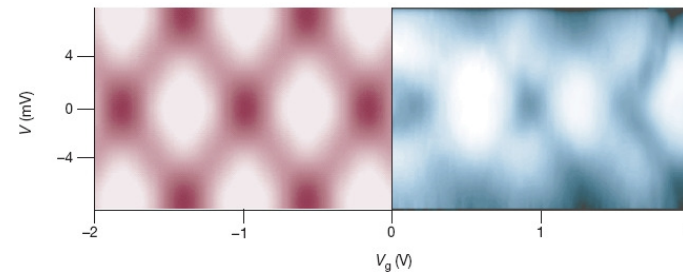
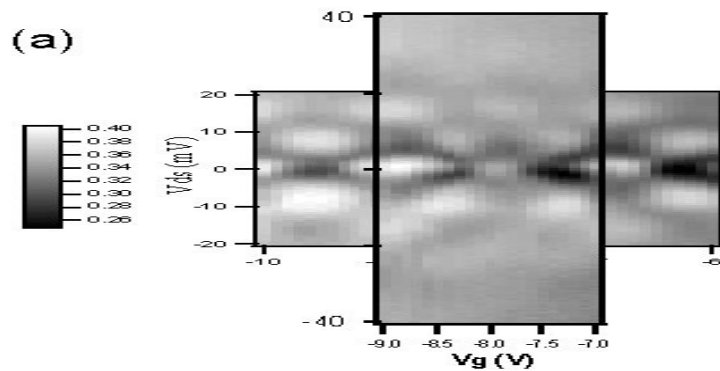
Sample



Model



Measurements:



(Liang et al. Nature)

Problem: why the fabry-perot pattern is vanishing at high bias?
This cannot be explained by FL theory, the authors exclude heating effects.

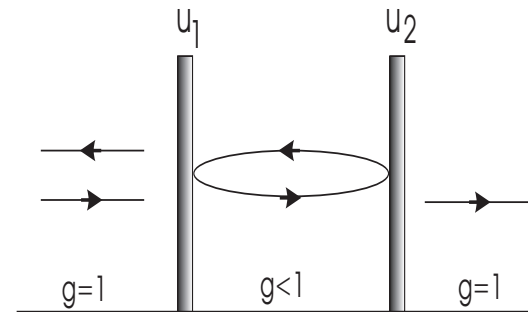
Tomonaga-Luttinger Liquid

Model:

They model the system as TLL with two barriers separating the metal reservoirs from the SWNT and with spatially inhomogeneous interaction parameter g . the interaction is strong in the SWNT ($0 < g < 1$) and weak in the reservoirs ($g = 1$).

Luttinger liquid:

In a one dimensional system of interacting electrons the Fermi Liquid theory doesn't work!



In particular the 4 conducting transverse modes of the SWNT in are transformed to four collective excitations in the TLL theory: one interacting collective mode ($a=1$, $g_a = g$) of the total charge and three non-interacting collective modes ($a=2-4$, $g_a = 1$) including spin. These modes are partially reflected at the two barriers. The interacting mode further experiences momentum-conserving reflections due to the mismatch of g at the interfaces*.

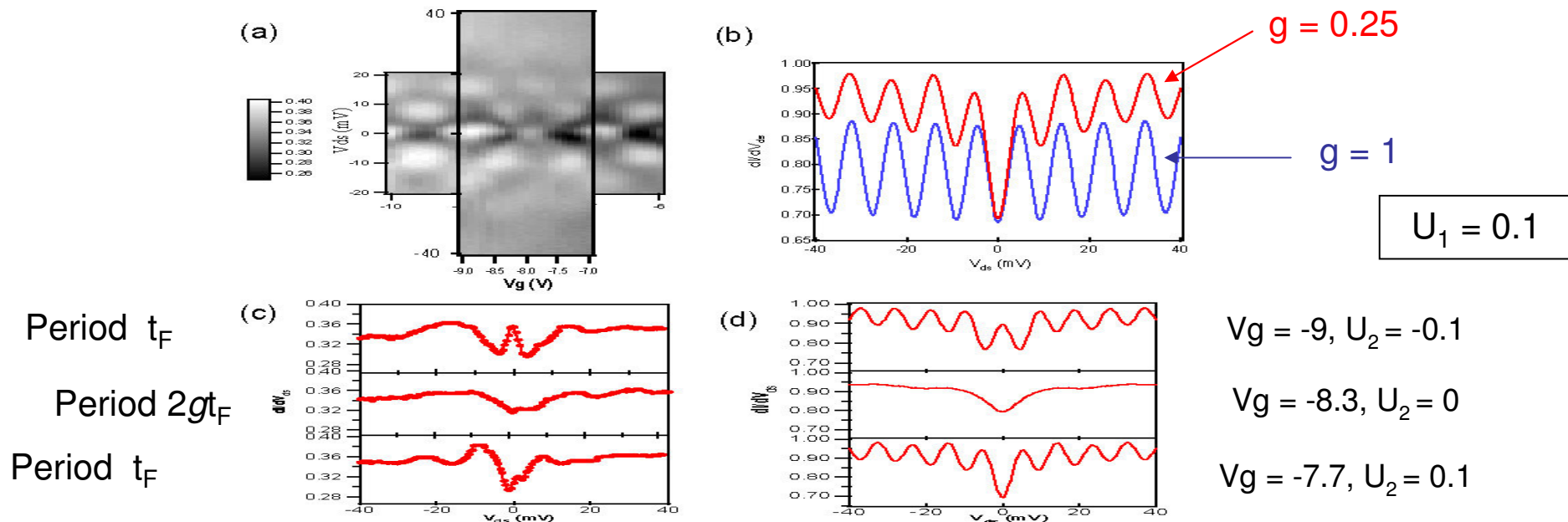
Measurements vs Simulations

They use the Keldish formalism and treat the barrier as perturbation, then the backscattered amplitudes is given by:

$$I_B = \frac{2e}{\pi t_F^2} \sum_{n=1,2} U_n \left| \int_0^\infty dt e^{C_n(t)} \sin\left(\frac{R_n(t)}{2}\right) \sin\left(\frac{eV_{ds}t}{\hbar}\right) \right|$$

Where $t_F = L / v_F$, it's the non-interacting traveling time. **U1** represent incoherent backscattering at the barriers.

U2 represent the coherent contribution resulting in the FP oscillations.



To identify LL features uniquely we have to have $eV_{ds} > \hbar / (2g t_F)$
 The extracted $g \sim 0.22$ from the measurements.

Shot Noise Measurements

Noise is not only caused by bad experimentalists!:

In particular **shot noise** is related to the granularity of the current and contain information about the microscopic mechanism of the conduction process.

In gernal, the noise p.s. d. is given by :

$$S_{\text{SWNT}}(\omega) = \int dt e^{i\omega t} \langle \{ \delta \hat{I}(t), \delta \hat{I}(0) \} \rangle$$

In case of Poisson statistics the noise power spectral density (noise p.s.d) S:

$$S_{\text{poission}} = 2eI \quad (\text{assuming the current carryed by electrons})$$

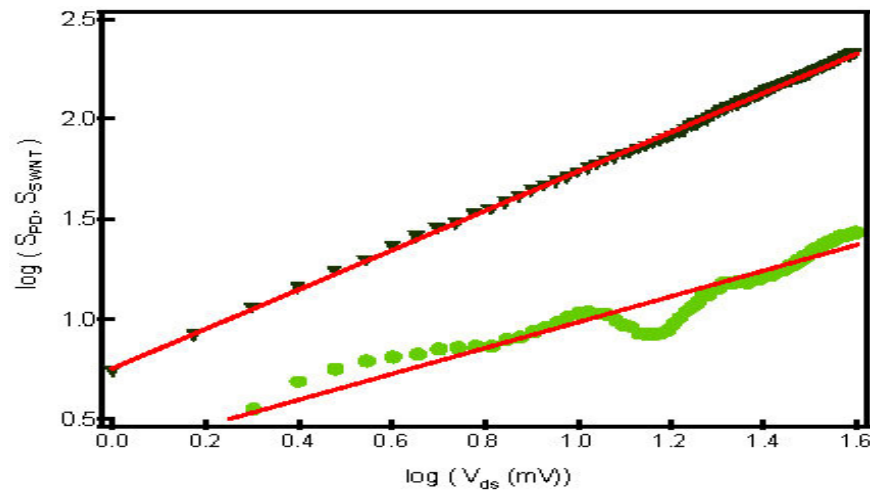
The **Fano Factor** is defined as the ratio of measured noise p.s.d and to the full shot noise value:

$$F = S / 2eI$$

Shot Noise Measurements

Technique:

The measurements were performed by placing two current noise sources in parallel: a SWNT device and a full shot noise generator a weakly coupled lightemitting diode (LED) and photodiode (PD) pair (a full shot noisegenerator) .



They implemented an AC modulation lock-in technique and designed a resonant tank-circuit ($f = 15 \text{ Mhz}$) together with a home-built cryogenic low-noise preamplifier $2.2\text{nV}/\sqrt{\text{Hz}}$.

The measurements were performed at 4 kelvin

Power spectral density within their Luttinger Liquid model:

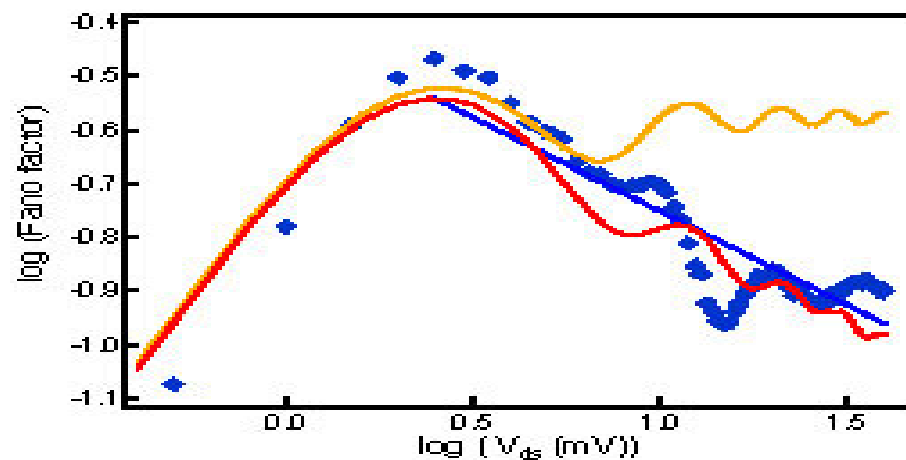
Calculated noise p.s.d :

$$S_{\text{SWNT}}(\omega) = \int dt e^{i\omega t} \langle \{ \delta \hat{I}(t), \delta \hat{I}(0) \} \rangle =$$

$$= 2e \coth(eV_{\text{ds}}/2k_{\text{B}}T) I_{\text{B}} + 4k_{\text{B}}T (dI/dV_{\text{ds}} - dI_{\text{B}}/dV_{\text{ds}})$$

where $I_{\text{B}} = \frac{2e}{\pi t_{\text{F}}^2} \sum_{n=1,2} U_n \left| \int_0^\infty dt e^{C_n(t)} \sin\left(\frac{R_n(t)}{2}\right) \sin\left(\frac{eV_{\text{ds}}t}{\hbar}\right) \right|$

Measured Fano Factor



$g = 1$

$g = 0.18$

$g = 0.25$

First region $eV_{\text{ds}} < kT < \hbar / 4\pi g t_{\text{F}}$

- $F(I) \sim V_{\text{ds}}$

Second region $eV_{\text{ds}} > \hbar / 4\pi g t_{\text{F}}$

- $F(I) \sim (V_{\text{ds}})^{\alpha}$

• Good agreement with the previous found values of g